

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10560048	SATO ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	SHEELA C CHAWAN	2624

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	154, 254, 256, 257, 276, 282, 310, 283, 162, 165. 190, 181191,	12/21/08	scc
209	580, 939	"	"
356	71, 336, 335	"	"
348	207.99, 254, 222.1, E5.024, 584, 586, 571, 578, 255, 126, E5.029, E5.036, E5.041, E5.115, E5.037, 364	"	"
205	574	"	"
382	154,165	7/18/09	SCC
250	574	7/18/09	SCC
348	E5.029	7/18/09	SCC
ABOVE SEARCH UO- DATE.		7/18/09	SCC

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY.	12/21/08	SCC
INVENTOR SEARCH.	"	"
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY,	7/18/09	SCC
382/154,149,283,257,165,191,254,100,141,145,276,282,283,165,162,181 .CCLS. US-PATENT TEXT SEARCH ONLY.	7/18/09	SCC
250/574,200,216,573,574.CCLS. US-PATENT TEXT SEARCH ONLY.	7/18/09	SCC
348/126,E5.073,222.1,E5.041,E5.115,E5.037,364,E5.029,E5.036,586,229 .1.CCLS.US-PATENT TEXT SEARCH ONLY.	7/18/09	SCC
INTERFERENCE SEARCH	7/18/09	SCC
SEARCH IEEE OR INSPEC DATA.BASE.	7/18/09	SCC
SEARCH UP-DATE	7/18/09	SCC

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	154, 156	7/18/09	SCC

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
250	574	7/18/09	SCC
348	E5.029	7/18/09	SCC